Candidate text for Annex 93A, Clause 110 and Clause 111

Adee Ran

Modified transition time equation i-49, i-50, i-57, i-61, i-88

93A.2 Test channel calibration using COM

Change the paragraph before Equation (93A-46) and Equation (93A-46) as follows:

If the test transmitter presents a high-quality termination, e.g., it is a piece of test equipment, the transmitter device package model $S_p^{(ip)}$ is omitted from the calculation of $S_p^{(ik)}$. Instead, the voltage transfer function is multiplied by the filter $H_i(f)$ defined by Equation (93A-46), where T_p is the 20 to 80% transition time (see 86A.5.3.3) of the signal as measured at TP0a and A is 1 unless indicated otherwise in the PMD clause that invokes this method.

$$H_t(f) = \exp(-A(\pi f T_r / 1.6832)^2)$$
 (93A-46)

Substitute β for A

i-68, i-69 "Supports operation"

110.1 Overview

A 25GBASE-CR PHY supports operation operates over cable assemblies of types CA-25G-N, CA-25G-S and CA-25G-L (see 110.10). A 25GBASE-CR-S PHY supports operation operates over cable assemblies of types CA-25G-N and CA-25G-S, but not CA-25G-L. A 25GBASE-CR-S PHY interoperates with a 25GBASE-CR PHY.

110.6 FEC modes

The cable assembly types (CA-25G-N, CA-25G-S or CA-25G-L, see 110.10) that the PHY supports operates over and the required PMD receiver characteristics (110.8.4) depend on the FEC mode.

110.10 Cable assembly characteristics

- a) Cable assembly long (CA-25G-L): Cable assembly that supports links between can be used to connect two PHYs that operate in RS-FEC mode with error correction enabled on both receivers, with achievable cable length of at least 5 m.
- b) Cable assembly short (CA-25G-S): Cable assembly that supports links between can be used to connect two PHYs that operate in BASE-R FEC mode, with achievable cable length of at least 3 m.
- c) Cable assembly no-FEC (CA-25G-N): Cable assembly that supports links between can be used to connect two PHYs that operate in no-FEC mode, with achievable cable length of at least 3 m.

i-25: references to clause 92 and 93

110.8.4 Receiver characteristics

Receiver electrical characteristics <u>are specified</u> at <u>TP3 for 25GBASE-CR and 25GBASE-CR-S PHYs TP3</u>. A receiver shall be meet the same as those of a single lane of 100GBASE-CR4, as summarized return loss requirements specified in <u>Table 92-7 and detailed in 92.8.4.2, 92.8.4.3-2</u> and 92.8.4.63. In addition, the requirements in 110.8.4.1, 110.8.4.2, 110.8.4.3 and 110.8.4.4 apply.

111.8.3 Receiver characteristics

Receiver electrical characteristics are specified at TP5a for 25GBASE-KR TP5a. A receiver shall be meet the same as those of a single lane of 100GBASE-KR4, as summarized return loss requirements specified in Table 93-5 and detailed in 93.8.2.1 through 2 measured using the test fixture of 93.8.2.41. In addition, the requirements in 111.8.3.1 and 111.8.3.2 apply.

Clause 110 test setup/channel i-71

110.8.4.2.1 Test setup

The interference tolerance test is performed with the setup shown in Figure 110–3. The requirements of this subclause are verified at the pattern generator connection (PGC) or test references in Figure 110–3 and Figure 110–4. The cable assembly unused single-ended paths are terminated in 50 Ω to provide 100 Ω differential termination.

110.8.4.2.2 Test channel

The test channel (depicted in Figure 110-3) consists of the following:

- a) A cable assembly (see meeting the requirements of 110.10) that meets, and the eable assembly COM fitted insertion loss specified for the test being performed.
- A cable assembly test fixture (see 110B.1.2 and 92.11.2).
- c) A connecting path from the pattern generator to the cable assembly test fixture.
- A frequency-dependent attenuator.

NOTE—The frequency-dependent attenuator represents the host channel and may be implemented with PCB traces and test cables.

Clause 110 test setup/channel i-71, i-73, i-74

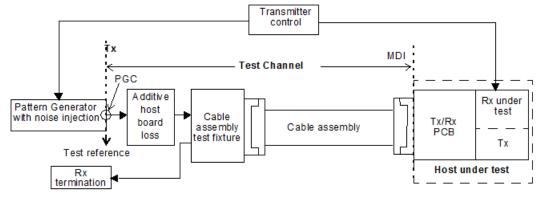
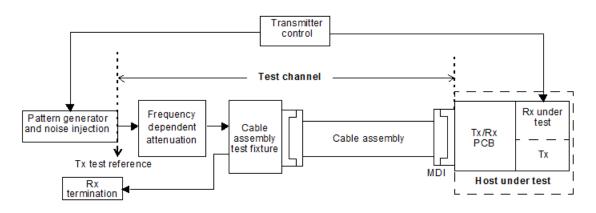


Figure 110-3—Interference tolerance test setup



NOTE—The MDI of the host under test is not included in the test channel.

Figure 110-3-Interference tolerance test setup

Clause 110 test setup/channel i-71, i-74

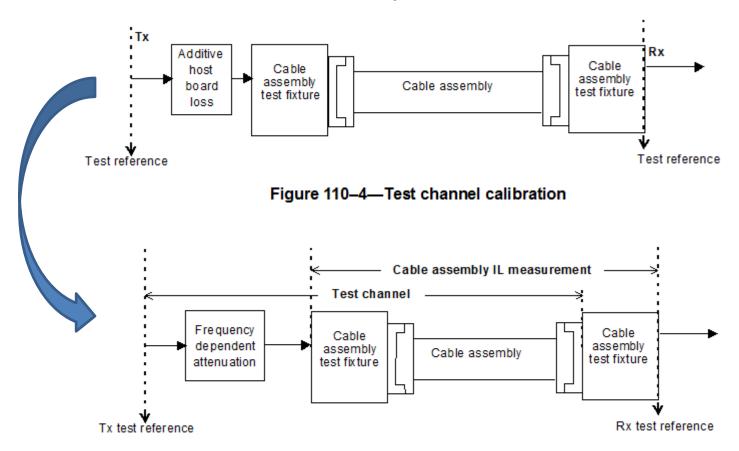


Figure 110-4—Test channel calibration

Pattern generator i-81

110.8.4.2.4 Pattern generator

110.8.4.2.5 Pattern generator and noise injection

The pattern generator transmits data to the device under test. At the start of transmitter training, the pattern generator output amplitude shall be 800 mV peak-to-peak differential when measured on an alternating one-zero pattern. The output amplitude, measured on an alternating one-zero pattern, is not permitted to exceed 800 mV peak-to-peak differential during transmitter training. The output waveform of the pattern generator shall comply with 110.8.1.

The pattern generator shall be set to match the jitter specification specified for the test being performed. The Broadband noise is added to the test pattern generator shall inject broadband noise on before the data signal TX test reference point, with noise level set according to step e) in 110.8.4.2.3.

Test procedure (see ran_3by_01_0116)

110.8.4.2.6 Test procedure

The pattern generator is first configured to transmit the training pattern defined in 110.7.10. During this initialization period, the device under test (DUT) configures the pattern generator equalizer, via transmitter control, transmit equalizer to the coefficient settings it would select using the protocol start-up, described in 72.6.10 and the receiver is tuned using its optimization method. The coefficient settings may be communicated via the start-up protocol or by other means.

COM for the RITT, Clause 110 i-24, i-48, i-51, i-66, i-71

The COM shall be calculated using the method and parameters of 110.10.7 with the following exceptions:

- a) The channel signal path is $\frac{SCHS_p = cascade(S^{(CTSP)}, S^{(HOSP)})}{SCHS_p = cascade(S^{(CTSP)}, S^{(HOSP)})}$, where $\frac{S^{(CTSP)}}{SCHS_p}$ are defined in 110.10.7.1.1 and $\frac{S^{(CTSP)}}{SCHS_p}$ is the measured channel between the test references in Figure 110–8.
- b) The COM parameters are as modified by Table 110-6, Table 110-8 or Table 110-10, as appropriate for the test being perform ed.
- c) COM is calculated using the two different device package model transmission line lengths listed for Test 1 and Test 2 in Table 110-10 The value of COM is taken as the lower of the two calculated values.
- d) Even-odd jitter, EBUJ and ERJ without noise injection (see 110.8.4.2.5) are measured at the Tx test reference point and comply with the specifications in 92.8.3.8.1 and 92.8.3.8.2. In the calculation of COM, A_{DD} is set to half of the value of EBUJ and σ_{RJ} is set to the value of ERJ, replacing the values in Table 1110-10. It is recommended to adjust the pattern generator jitter such that the effective
 - bounded uncorrelated jitter and the effective total uncorrelated jitter are as close as practical to their limits in Table 92-6.
- e) SNDR of the pattern generator after noise injection (see 110.8.4.2.5) is measured at the PGC-Tx test reference point using the procedure in 92.8.3.7. The resulting value is used as SNR_{TX} in calculation of COM. The level of noise injected is adjusted until the required COM is achieved for the test.
- f) If the pattern generator presents a high-quality termination, e.g., it is a piece of test equipment, the The transmitter device package model S^(p) is omitted from the calculation of S_p S_p. Instead, the voltage transfer function is multiplied by the filter H_t(f) defined by Equation (92-22) Equation (93 A-46) where β is 2 and T_p is the 20% to 80% transition time (see at the Tx test reference point. T_p is measured with preset equalizer values using the method in 86 A.5.3.3) of with the signal as measured at exception that the PGC reference point observation filter bandwidth is 33 GHz instead of 12 GHz.

COM for the RITT, Clause 111 i-50, i-51, i-57, i-61, i-66, i-88

111.8.3.1 Receiver interference tolerance

The receiver interference tolerance test setup and method are as specified in 93.8.2.3, for a single lane, with the exception that the test requirements in this subclause replace the test requirements in Table 93.6. The test requirements for RS-FEC mode are provided in Table 111.4. The test requirements for BASE-R FEC mode are provided in Table 111.6 following expressions:

- a) The test requirements in this subclause replace the test requirements in Table 93-6. The test requirements for RS-FEC mode are provided in Table 111-4. The test requirements for BASE-R FEC mode are provided in Table 111-5. The test requirements for no-FEC mode are provided in Table 111-6.
- b) The test channel COM is calculated with the transmitter device package model $S^{(tp)}$ omitted from the calculation. Instead, the voltage transfer function is multiplied by the filter $H_t(f)$ defined by Equation (93A-46) where β is 2, T_z is calculated as $T_z = 1.09 \times T_z^{measured} 4.32$, and $T_z^{measured}$ is the 20% to 80% transition time of the signal at TP0a. $T_z^{measured}$ is measured with preset equalizer values using the method in 86A.5.3.3, with the exception that the filter bandwidth is 33 GHz instead of 12 GHz.
- c) COM is calculated using the two different device package model transmission line lengths listed for Test 1 and Test 2 in Table 111-8. The value of COM is taken as the values.
 of the two calculated
- d) Even-odd jitter at TP0a is subject to the specification of 92.8.3.8.1.

It is recommended to adjust the test transmitter jitter such that the effective bounded uncorrelated jitter and the effective total uncorrelated jitter are as close as practical to their limits in Table 93-4.

Fitted insertion loss vs. parameters i-36, i-37

The fitted insertion loss ecoefficients—at 12.8906 GHz of the signal path between the reference points in 110-4, derived using the fitting procedure in 92.10.2, shall meet be within the values limits in Table 110-5, Table 110-6, or Table 110-7, as appropriate for the test being performed. It is recommended that the deviation between the insertion loss and the fitted insertion loss be as small as practical and that the fitting parameters be as close as practical to the values given in the table.

Receiver jitter tolerance, Clause 110 i-29

110.8.4.3 Receiver jitter tolerance

Jitter tolerance in RS-FEC mode is measured with a channel meeting the channel fitted insertion loss of test 2 and the RS-FEC symbol error requirement of test 2 as specified in Table 110-5. Jitter tolerance in BASE-R FEC mode is measured with a channel meeting the channel and error requirement fitted insertion loss of test 2 and the corrected and uncorrected block ratio requirements as specified in Table 110-6. Jitter tolerance in no-FEC mode is measured with a channel meeting the channel fitted insertion loss of test 2 and the bit error ratio requirement of test 2 as specified in Table 110-7.

The test setup shown in Figure 110-3, or its equivalent, is used. The pattern generator meets the requirements of 110.8.4.2.4 except that no broadband noise is injected during the test, and the jitter is set to the frequency and peak-to-peak amplitude values specified in Table 110-8 instead. The test procedure is the same as the one described in 110.8.4.2.5.

Receiver jitter tolerance is verified for each pair of jitter frequency and peak-to-peak amplitude values listed in Table 110-8. The test setup and procedure of 110.8.4.2 are used, with the exception that no noise is injected (COM calibration, as in step e in 110.8.4.2.3, is not performed), and instead, the specified jitter frequency is applied to the transmitter and the jitter amplitude is adjusted to obtain the specified peak-to-peak jitter for that frequency at the Tx test reference.

Receiver jitter tolerance, Clause 111 i-29

111.8.3.2 Receiver jitter tolerance

Jitter tolerance in the RS-FEC mode is measured with a channel meeting the channel fitted insertion loss of test 2 and the RS-FEC symbol error requirement of test 2 as specified in Table 111-4. Jitter tolerance in the BASE-R FEC mode is measured with a channel meeting the channel and error requirement fitted insertion loss of test 2 and the corrected and uncorrected block ratio requirements as specified in Table 111-5. Jitter tolerance in the no-FEC mode is measured with a channel meeting the channel fitted insertion loss of test 2 and the bit error ratio requirement of test 2 as specified in Table 111-6.

Removing fitting coefficients C111 i-28

Table 111–4—25GBA SE-KR interference tolerance parameters, RS-FEC mode

	Test 1 (low loss)		Test 2 (high loss)		
Parameter	Min	Max	Min	Max	Units
Insertion loss at 12.89 GHz ^a	_	30	35	_	dВ
Fitted insertion loss coefficients ^b $\begin{array}{c} a_0 \\ a_1 \\ a_2 \\ a_4 \end{array}$	-0.9 0 0 0	0.9 3.3 — 0.03	-0.9 0 0 0	0.9 3.3 — 0.043	dB dB/GHz ^{1/2} dB/GHz dB/GHz ²
COM	_	3	_	3	₫B
Test pattern	Scram	bled idle en	coded by R	S-FEC	
RS-FEC symbol error ratio required ^c	< 10 ⁻⁴				
b _{m ax} used in COM calculation	1				
DER ₀ used in COM calculation		10)–5		

^aMeasured between TPt and TP5 (see Figure 93C-4).

Table 111–4—25GBA SE-KR interference tolerance parameters, RS-FEC mode

Parameter	Test 1 (low loss)	Test 2 (l	nigh loss)	Units
rarameter	Min	Max	Min	Max	Units
Fitted insertion loss at 12.8906 GHz ^a	16	16.5	35	35.5	dΒ
COM	_	3	_	3	dB
Test pattern	Scrambled idle encoded by RS-FEC				
RS-FEC symbol error ratio required ^b	< 10 ⁻⁴				
b_{\max} used in COM calculation	1				
DER ₀ used in COM calculation		10) ⁻⁵		

^aMeasured between TPt and TP5 (see Figure 93C-4).

bCoefficients are calculated from the insertion loss measured between TPt and TP5 (see Figure 93C-4) using the method in 93A.3 with f_{min}=0.05 GHz, f_{max}=25.78125 GHz, and maximum Δf=0.01 GHz. ^cThe RS-FEC symbol error ratio is measured using the RS-FEC symbol error counter (see 108.6.9).

bThe RS-FEC symbol error ratio is measured using the RS-FEC symbol error counter (see 108.6.9).

Removing fitting coefficients C111 i-28

Table 111–5—25GBA SE-KR and 25GBA SE-KR-S interference tolerance parameters, BA SE-R FEC mode

Parameter	Test 1 (low loss)		Test 2 (high loss)		
rarameter	Min	Max	Min	Max	Units
Insertion loss at 12.89 GHz ^a	_	16	30	_	dB
Fitted insertion loss coefficients ^b a_0 a_1 a_2 a_4	-0.9 0 0 0	0.9 3.3 — 0.022	-0.9 0 0 0	0.9 3.3 — 0.03	dB dB/GHz ^{1/2} dB/GHz dB/GHz ²
COM	_	3	_	3	đΒ
Test pattern	Scramble	d idle enco	ded by BAS	E-R FEC	
BASE-R FEC block error ratio required ^c	< 2.1×10 ⁻⁵				
$b_{ m max}$ used in COM calculation	0.5				
DER ₀ used in COM calculation		10) - 8		

^aMeasured between TPt and TP5 (see Figure 93C-4).

Table 111–5—25GBA SE-KR and 25GBA SE-KR-S interference tolerance parameters, BA SE-R FEC mode

	Test 1 (low loss)	Test 2 (l	nigh loss)	
Parameter Parameter	Min	Max	Min	Max	Units
Fitted insertion loss at 12.8906 GHz ^a	16	16.5	30	30.5	đВ
COM	T -	3	_	3	dВ
Test pattern	Scrambled idle encoded by BASE-R FEC				
Corrected block ratio ^b		< 2.1×10 ⁻⁵			
Uncorrected block ratio ^c	< 4.7×10 ⁻¹⁰				
b_{\max} used in COM calculation	0.5				
DER ₀ used in COM calculation		10) - 8		

^aMeasured between TPt and TP5 (see Figure 93C-4).

bCoefficients are calculated from the insertion loss measured between TPt and TP5 (see Figure 93C-4) using the method in 93A.3 with f_{min}=0.05 GHz, f_{max}=25.78125 GHz, and maximum Δf=0.01 GHz. ^CThe BASE-R FEC block error ratio is the number of blocks that contain errors divided by the total num-

^cThe BASE-R FEC block error ratio is the number of blocks that contain errors divided by the total number of blocks received. The number of blocks that contain errors is measured using the sum of the FEC corrected blocks counter (see 74.8.4.1) and the FEC uncorrected blocks counter (see 74.8.4.2).

^bThe corrected block ratio is measured using the FEC corrected blocks counter (see 74.8.4.1).

^cThe uncorrected block ratio is measured using the FEC uncorrected blocks counter (see 74.8.4.2).

Removing fitting coefficients C111 i-28

Table 111–6—25GBA SE-KR and 25GBA SE-KR-S interference tolerance parameters, no-FEC mode

Parameter	Test 1 (low loss)		Test 2 (high loss)		***
rarameter	Min	Max	Min	Max	Units
Insertion loss at 12.89 GHz ^a	_	16	30	_	dB
Fitted insertion loss coefficients ^b a_0 a_1 a_2 a_4	-0.9 0 0 0	0.9 3.3 — 0.022	-0.9 0 0 0	0.9 3.3 — 0.03	dB dB/GHz ^{1/2} dB/GHz dB/GHz ²
COM	_	3	_	3	đΒ
Test pattern	S	crambled id	le or PRBS	31	
Bit error ratio required ^c	< 10 ⁻¹²				
$b_{\rm max}$ used in COM calculation	0.35				
DER ₀ used in COM calculation		10	-12		

^aMeasured between TPt and TP5 (see Figure 93C-4).

Table 111–6—25GBA SE-KR and 25GBA SE-KR-S interference tolerance parameters, no-FEC mode

Parameter	Test 1 (Test 1 (low loss) Test 2 (high loss)	***
Parameter	Min	Max	Min	Max	Units
Fitted insertion loss at 12.8906 GHz ^a	16	16.5	30	30.5	dВ
COM	_	3	_	3	đВ
Test pattern	S	Scrambled idle or PRBS31			
Bit error ratio required ^b		< 10 ⁻¹²			
b_{\max} used in COM calculation	0.35				
DER ₀ used in COM calculation		10	-12		

^aMeasured between TPt and TP5 (see Figure 93C-4).

bCoefficients are calculated from the insertion loss measured between TPt and TP5 (see Figure 93C-4) using the method in 93A.3 with f_{min}=0.05 GHz, f_{max}=25.78125 GHz, and maximum Δf=0.01 GHz.
cThe bit error ratio is measured using the PCS errored blocks counter (see 49.2.14.2) or the PMA

^cThe bit error ratio is measured using the PCS errored blocks counter (see 49.2.14.2) or the PMA PRBS31 error counter (see 109.4.4.4) as appropriate.

The bit error ratio is measured using the PCS errored blocks counter (see 49.2.14.2) or the PMA PRBS31 error counter (see 109.4.4.4) as appropriate.

Cable assembly characteristics: i-87

Table 110-9—Cable assembly characteristics summary

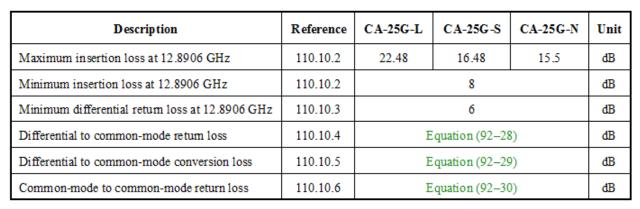


Table 110–9—Cable assembly characteristics summary

Description	Reference	CA-25G-L	CA-25G-S	CA-25G-N	Unit
Maximum insertion loss at 12.8906 GHz	110.10.2	22.48	16.48	15.5	ďΒ
Minimum insertion loss at 12.8906 GHz	110.10.2	8			dΒ
Minimum differential return loss at 12.8906 GHz	110.10.3	6			ďΒ
Differential to common-mode return loss	110.10.4	Equation (92-28)			ďΒ
Differential to common-mode conversion loss	110.10.5	Equation (92-29)			ďΒ
Common-mode to common-mode return loss	110.10.6	Equation (92-30)			ďΒ
COM (minimum)	110.10.7	S	ee Table 110-1	10	

110.10.2 Cable assembly insertion loss

The fitted cable assembly insertion loss IL fitted (f) as a function of frequency f is defined in Equation (92-23).

C110 RITT table changes i-51, i-36, i-37

Table 110-5—25GBASE-CR interference tolerance parameters, RS-FEC mode

P ar am et er	Test 1 (low loss)	Test 2 (high loss)	Units	
Test pattern	Scrambled idle en			
RS-FEC symbol error ratio required ^a	< 1	< 10 ⁻⁴		
Fitted in sertion loss coefficients a_1 a_2 a_4	1.7 0.546 0.01	4.3 0.571 0.04	dB/GHz ¹ dB/GHz dB/GHz ²	
Approximate fitted loss at 12.89 GHz ^b	14.8	29.44	dB	
Applied SJ ^c (peak-to-peak)	0	.1	T 11	
Applied RJ (RMS)	0.	01	Table '	
Even-odd jitter	0.0)35		
COM (m ax)		3	Pai	

10-5



Table 110-5—25GBA SE-CR interference tolerance parameters, RS-FEC mode

^a The RS-FEC symbol error ratio is measured using the RS-FEC symbol error
^b Fitted insertion loss between the two test reference points (see Figure 110-4
^c Applied SJ frequency >100 MHz, specified at TP0.

Parameter	Test 1 (Test 1 (low loss)		T est 2 (high loss)	
rarameter	Min	Max	Min	Max	Units
Test pattern	Scram	Scrambled idle encoded by RS-FEC			
RS-FEC symbol error ratio required ^a	< 10 ⁻⁴				
Test channel fitted insertion loss at 12.8906 GH z ^b	14.3	14.8	29.44	29.94	₫B
Cable assembly fitted insertion loss at 12.8906 GHz	8	10	20.48	22.48	dB
COM		3		3	dB
b _{max} used in COM calculation	1				
DER ₀ used in COM calculation		10) ^{–5}		

^aThe RS-FEC symbol error ratio is measured using the RS-FEC symbol error counter (see 108.6.9). ^bFitted insertion loss between the two test reference points (see Figure 110-4).

 $b_{\rm max}$ used in COM calculation

DER₀ used in COM calculation

C110 RITT table changes i-51, i-36, i-37, i-105

Table 110–6—25GBASE-CR and 25GBASE-CR-S interference tolerance parameters, BASE-R FEC mode

P ar am et er	Test 1 (low loss)	Test 2 (high loss)	Units
Test pattern	Scrambledidle enco		
BASE-R FEC block error ratio required ^a	< 2.1		
Fitted insertion loss coefficients a_1 a_2 a_4	1.7 0.546 0.01	3.42 0.4721 0.03055	dB/GHz ^{1/2} dB/GHz dB/GHz ²
Approximate fitted loss at 12.89 GHz ^b	14.8	23.44	₫B
Applied SJ ^c (peak-to-peak)	0	UI	



Table 110–6—25GBASE-CR and 25GBASE-CR-S interference tolerance parameters, BASE-R FEC mode

P ar am et er	Test 1 (low loss)	Test 2 (high loss)	Units
Applied RJ (RMS)	0.01		UI
Even-odd jitter	0.0	UI	
COM (m ax)	3	₫B	
$b_{ m max}$ used in COM calculation	0.5		
DER ₀ used in COM calculation	10)-8	

^aThe BASE-R FEC block error ratio is the number of blocks that contain errors divided by the total number of blocks received. The number of blocks that contain errors is measured using the sum of the FEC corrected blocks counter (see 74.8.4.1) and the FEC uncorrected blocks counter (see 74.8.4.2). ^bFitted insertion loss between the two test reference points (see Figure 110–4).

Table 110–6—25GBA SE-CR and 25GBA SE-CR-S interference tolerance parameters, BA SE-R FEC mode

Parameter	Test 1 (low loss)		T est 2 (high loss)		
	Min	Max	Min	Max	Units
Test pattern	Scrambled idle encoded by BASE-R FEC				
Corrected block ratio required ^a	< 2.1×10 ⁻⁵				
Uncorrected block ratio required ^b	< 4.7×10 ⁻¹⁰				
Test channel fitted insertion loss at 12.8906 GH z ^c	14.3	14.8	23.44	23.94	dB
Cable assembly fitted insertion loss at 12.8906 GHz	8	10	14.48	16.48	dB
COM		3		3	dB
$b_{ m max}$ used in COM calculation	0.5				
DER ₀ used in COM calculation	10 ⁻⁸				

^aThe corrected block ratio is measured using the FEC corrected blocks counter (see 74.8.4.1).

^cApplied SJ frequency >100 MHz, specified at TP0.

^bThe uncorrected block ratio is measured using the FEC uncorrected blocks counter (see 74.8.4.2).

cFitted insertion loss between the two test reference points (see Figure 110-4).

C110 RITT table changes i-51, i-36, i-37

Table 110–7—25GBASE-CR and 25GBASE-CR-S interference tolerance parameters, no-FEC mode

P ar am et er	Test 1 (low loss)	Test 2 (high loss)	Units
Test pattern	Scrambled id		
Bit error ratio required ^a	< 1		
Fitted insertion loss coefficients a_1 a_2 a_4	1.7 0.546 0.01	3.28 0.4424 0.0301	dB/GHz ^{1/2} dB/GHz dB/GHz ²
Approximate fitted loss at 12.89 GHz ^b	14.8	22.48	dB
Applied SJ ^c (peak-to-peak)	0	UI	
Applied RJ (RMS)	0.	UI	
Even-odd jitter	0.0	UI	
COM (m ax)	3	2.2	dB
b _{max} used in COM calculation	0.		
DER ₀ used in COM calculation	10		

^aThe bit error ratio is measured using the PCS errored blocks counter (see 49.2.14.2) or the PMA PRB S31 error counter (see 109.4.4.4) as appropriate.



Table 110–7—25GBA SE-CR and 25GBA SE-CR-S interference tolerance parameters, no-FEC mode

Parameter	Test 1 (low loss)		T est 2 (high loss)		
	Min	Max	Min	Max	Units
Test pattern	Scrambled idle or PRB S31				
Bit error ratio required ^a	< 10 ⁻¹²				
Test channel fitted insertion loss at 12.8906 GHz ^b	14.3	14.8	22.48	22.98	dB
Cable assembly fitted insertion loss at 12.8906 GHz	8	10	13.5	15.5	dB
COM		3		2.2	dB
$b_{ m max}$ used in COM calculation	0.35				
DER ₀ used in COM calculation	10 ⁻¹²				

^aThe bit error ratio is measured using the PCS errored blocks counter (see 49.2.14.2) or the PMA PRB S31 error counter (see 109.4.4.4) as appropriate.

^bFitted insertion loss between the two test reference points (see Figure 110-4).

^cApplied SJ frequency >100 MHz, specified at TP0.

^bFitted insertion loss between the two test reference points (see Figure 110-4).